



## Imaging with Electromagnetic Waves: Principles and Applications

Guest Editor:

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### **Message from the Guest Editor**

It is well known that any spectral range of the Electromagnetic (EM) wave spectrum can be used to take images of a scene/object. X-ray, panchromatic, spectral, infrared, tera-hertz, mm, M/W, Synthetic Aperture Radar (SAR), and Ground Penetrating Radar (GPR) are very well known images taken with different EM spectral ranges, since different EM spectral ranges reveal different characteristics of resolving power, penetrating depth, color and composition identification, and thermal matching. For these reasons, each image has been very widely used for its specific purposes in different sciences, engineering, and industries, for diagnostics, mapping, and identification of objects/scenes being tested.

This Special Issue is devoted to reviewing the current technological status and new applications of such images.

Prof. JungYoung Son  
*Guest Editor*





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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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